

APPLICATION DATA SHEET

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INVENTOR INFORMATION

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CORRESPONDENCE INFORMATION

Correspondence customer number:: 23911

APPLICATION INFORMATION

Title line one:: INSPECTION OBJECT SILICON WAFER
Title line two:: FOR THE PURPOSE OF DETECTING
Title line three:: CRYSTAL DEFECTS AND THE METHOD
Title line four:: OF DETECTION THEREOF
Total drawing sheets:: 1
Formal drawings?: Yes
Application type:: utility
Docket Number:: 155/50324

REPRESENTATIVE INFORMATION

Representative customer number:: 23911

CONTINUITY INFORMATION

This application is a:: 371 of
Application one:: PCT/JP00/09135
Filing date:: 22 Dec 2000

PRIOR FOREIGN APPLICATIONS

Foreign application one:: 11-365947
Filing date:: 24 Dec 1999
Country:: Japan
Priority claimed:: Yes